

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/760,555	LEE ET AL.	
	<b>Examiner</b> Cong Van Tran	<b>Art Unit</b> 2617	

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
455	410 411	5/12/2007	CT